

SLUSAO0D-NOVEMBER 2011-REVISED NOVEMBER 2012

# 2.5A, Dual-Input, Single Cell Switchmode Li-Ion Battery Charger with Power Path Management and I<sup>2</sup>C Interface

Check for Samples: bq24160, bq24160A, bq24161, bq24161B, bq24163, bq24168

## FEATURES

- High-Efficiency Switch Mode Charger with Separate Power Path Control
  - Make a GSM Call with a Deeply Discharged Battery or No Battery
  - Instantly Start Up System from a Deeply Discharged Battery or No Battery
- Dual Input Charger
- Highly Integrated Battery N-Channel MOSFET Controller for Power Path Management
  - 20 V input rating, with Overvoltage Protection (OVP)
    - 6.5 V for USB Input
    - 10.5 V for IN input (bq24160, bq24160A, bq24161, bq24163)
    - 6.5 V for IN input (bq24168)
  - Integrated FETs for Up to 2.5A Charge Rate
    - Up to 2.5 A from IN Input (input current limit)
    - Up to 1.5 A from USB Input (input current limit)
- Safe and Accurate Battery Management Functions
  - 0.5% Battery Regulation Accuracy
  - 10% Charge Current Accuracy
- Charge Parameters Programmed Using I<sup>2</sup>C<sup>™</sup> Interface
  - Charge Voltage, Current, Termination Threshold, Input Current Limit, V<sub>INDPM</sub> Threshold, Watchdog and Safety Timers (disabled for bq24160A and bq24168)
- Voltage Based, NTC Monitoring Input
  - JEITA Compatible (bq24160, bq24160A, bq24161B, bq24163, bq24168)
- Thermal Regulation Protection for Output Current Control
- Low Battery Leakage Current, BAT Short-Circuit Protection
- Soft-Start Feature to Reduce Inrush Current
- Thermal Shutdown and Protection

 Available in small 2.8mm × 2.8mm 49-ball WCSP or 4mm × 4mm QFN-24 Packages

# APPLICATIONS

- Handheld Products
- Portable Media Players
- Portable Equipment
- Netbook and Portable Internet Devices

## DESCRIPTION

The bq24160, bq24160A, bq24161, bq24161B, bq24163, and bq24168 are highly integrated single cell Li-lon battery charger and system power path management devices targeted for space-limited, portable applications with high capacity batteries. The single cell charger has dual inputs which allow operation from either a USB port or higher-power input supply (that is, AC adapter or wireless charging input) for a versatile solution. The two inputs are fully isolated from each other and are easily selectable using the l<sup>2</sup>C interface.

## **APPLICATION SCHEMATIC**



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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

## **DESCRIPTION (CONTINUED)**

The power path management feature allows the bq2416x to power the system from a high-efficiency DC-to-DC converter while simultaneously and independently charging the battery. The charger monitors the battery current at all times and reduces the charge current when the system load requires current above the input current limit. This allows for proper charge termination and timer operation. Under normal battery charging conditions, the system voltage does not drop below 3.5V. This minimum system voltage support enables the system to run with a defective or absent battery pack and enables instant system turn-on even with a totally discharged battery or no battery. The power-path management architecture also permits the battery to supplement the system current requirements when the adapter cannot deliver the peak system currents. This enables the use of a smaller adapter. The 2.5A input current capability allows for GSM phone calls as soon as the adapter is plugged in regardless of the battery voltage. The charge parameters are programmable using the l<sup>2</sup>C interface.

The battery is charged in three phases: precharge, fast-charge constant current and constant voltage. In all charge phases, an internal control loop monitors the IC junction temperature and reduces the charge current if the internal temperature threshold is exceeded. Additionally, a voltage-based battery pack thermistor monitoring input (TS) is included that monitors battery temperature for safe charging. The TS function for bq24160, bq24160A, bq24161B, bq24163 and bq24168 is JEITA compatible.

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bg24160,	bq24160A
	bq24161B
bg24163	3, bq24168

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ORDERING INFORMATION									
PART NUMBER <sup>(1) (2)</sup>	USB OVP	IN OVP	USB DETECTION	TIMERS (Safety and Watchdog)	NTC MONITORING	V <sub>BATSHRT/</sub> I <sub>BATSHRT</sub>	V <sub>MINSYS</sub>	PKG	
bq24160YFFR	6.5V	10.5V	D+/D	Yes	JEITA	3.0V 50mA	3.5V	WCSP	
bq24160YFFT	6.5V	10.5V	D+/D-	Yes	JEITA	3.0V 50mA	3.5V	WCSP	
bq24160RGER	6.5V	10.5V	D+/D	Yes	JEITA	3.0V 50mA	3.5V	QFN	
bq24160RGET	6.5V	10.5V	D+/D	Yes	JEITA	3.0V 50mA	3.5V	QFN	
bq24160AYFFR	6.5V	10.5V	D+/D	No	JEITA	3.0V 50mA	3.5V	PREVIEW	
bq24160AYFFT	6.5V	10.5V	D+/D	No	JEITA	3.0V 50mA	3.5V	PREVIEW	
bq24160ARGER	6.5V	10.5V	D+/D	No	JEITA	3.0V 50mA	3.5V	QFN	
bq24160ARGET	6.5V	10.5V	D+/D	No	JEITA	3.0V 50mA	3.5V	QFN	
bq24161YFFR	6.5V	10.5V	PSEL (0=1.5A, 1=100mA)	Yes	Standard	2.0V 50mA	3.5V	WCSP	
bq24161YFFT	6.5V	10.5V	PSEL (0=1.5A, 1=100mA)	Yes	Standard	2.0V 50mA	3.5V	WCSP	
bq24161RGER	6.5V	10.5V	PSEL (0=1.5A, 1=100mA)	Yes	Standard	2.0V 50mA	3.5V	QFN	
bq24161RGET	6.5V	10.5V	PSEL (0=1.5A, 1=100mA)	Yes	Standard	2.0V 50mA	3.5V	QFN	
bq24161BYFFR	6.5V	10.5V	PSEL (0=1.5A, 1=500mA)	Yes	JEITA	3.0V 50mA	3.5V	WCSP	
bq24161BYFFT	6.5V	10.5V	PSEL (0=1.5A, 1=500mA)	Yes	JEITA	3.0V 50mA	3.5V	WCSP	
bq24161BRGER	6.5V	10.5V	PSEL (0=1.5A, 1=500mA)	Yes	JEITA	3.0V 50mA	3.5V	QFN	
bq24161BRGET	6.5V	10.5V	PSEL (0=1.5A, 1=500mA)	Yes	JEITA	3.0V 50mA	3.5V	QFN	
bq24163YFFR	6.5V	10.5V	D+/D-	Yes	JEITA	2.0V 50mA	3.2V	WCSP	
bq24163YFFT	6.5V	10.5V	D+/D-	Yes	JEITA	2.0V 50mA	3.2V	WCSP	
bq24163RGER	6.5V	10.5V	D+/D-	Yes	JEITA	2.0V 50mA	3.2V	QFN	
bq24163RGET	6.5V	10.5V	D+/D-	Yes	JEITA	2.0V 50mA	3.2V	QFN	
bq24168YFFR	6.5V	6.5V	PSEL (0=1.5A, 1=100mA)	No	JEITA	2.0V 50mA	3.5V	WCSP	
bq24168YFFT	6.5V	6.5V	PSEL (0=1.5A, 1=100mA)	No	JEITA	2.0V 50mA	3.5V	WCSP	

(1) The YFF and RGE packages are avaiable in the following options:

R - tabed and reeled in quantities of 3,000 devices per reel.

T - taped and reeled in quantities of 250 devices per reel.

(2) This product is RoHS compatible, including a lead concentration that does not exceed 0.1% of total product weight, and is suitable for use in specified lead-free soldering processes. In addition, this product uses package materials that do not contain halogens, including bromine (Br) or antimony (Sb) above 0.1% of total product weight.



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# ABSOLUTE MAXIMUM RATINGS

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over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

		VAL	VALUE	
		MIN	MAX	UNITS
	IN, USB	-2	20	V
Pin voltage range (with	PMIDI, PMIDU, BOOT	-0.3	20	V
respect to VSS)	SW	-0.7	12	V
	SDA, SCL, SYS, BAT, STAT, BGATE, DRV, TS, D+, D-, INT, PSEL, CD	-0.3	7	V
BOOT to SW	-0.3	7	V	
Outrut ourrest (Continuous)	SW			А
Output current (Continuous)	SYS, BAT	3.5		А
	IN	2.75		А
Input current (Continuous)	USB	1.75		А
Outruit sight surrout	STAT	10		mA
Output sink current	INT	1		mA
Operating free-air temperatur	e range	-40	85	°C
Junction temperature, T <sub>J</sub>	-40	125	°C	
Storage temperature, T <sub>STG</sub>	-65	150	°C	
Lead temperature (soldering,	10 s)	300		°C

(1) Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. All voltage values are with respect to the network ground terminal unless otherwise noted.

#### THERMAL INFORMATION

	THERMAL METRIC <sup>(1)</sup>	b	bq2416x			
		49 PINS (YFF)	24 PINS (RGE)	UNITS		
$\theta_{JA}$	Junction-to-ambient thermal resistance	49.8	32.6			
$\theta_{JCtop}$	Junction-to-case (top) thermal resistance	0.2	30.5			
$\theta_{JB}$	Junction-to-board thermal resistance	1.1	3.3	°C/W		
$\Psi_{JT}$	Junction-to-top characterization parameter	1.1	0.4	°C/w		
$\Psi_{JB}$	Junction-to-board characterization parameter	6.6	9.3			
$\theta_{\text{JCbot}}$	Junction-to-case (bottom) thermal resistance	n/a	2.6			

# (1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, SPRA953. **RECOMMENDED OPERATING CONDITIONS**

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNITS
	IN voltage range	4.2	18	
V <sub>IN</sub>	IN operating voltage range (bq24160/1/3)	4.2	10	V
	IN operating voltage range (bq24168)	4.2	6	
V	USB voltage range	4.2	18	V
V <sub>USB</sub>	USB operating range	4.2	6	v
I <sub>IN</sub>	Input current, IN input		2.5	А
I <sub>USB</sub>	Input current USB input		1.5	А
I <sub>SYS</sub>	Ouput Current from SW, DC		3	А
	Charging		2.5	А
IBAT	Discharging, using internal battery FET		2.5	А
TJ	Operating junction temperature range	0	125	°C



## **ELECTRICAL CHARACTERISTICS**

Circuit of ,  $V_{SUPPLY} = V_{USB}$  or  $V_{IN}$  (whichever is supplying the IC),  $V_{UVLO} < V_{SUPPLY} < V_{OVP}$  and  $V_{SUPPLY} > V_{BAT} + V_{SLP}$ ,  $T_J = -40^{\circ}C - 125^{\circ}C$  and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITI	IONS	MIN	TYP	MAX	UNIT
INPUT CURF	RENTS						
		$V_{UVLO} < V_{SUPPLY} < V_{OVP}$ and	PWM switching		15		mA
SUPPLY	Supply current for control (V <sub>IN</sub> or V <sub>USB</sub> )	V <sub>SUPPLY</sub> > V <sub>BAT</sub> +V <sub>SLP</sub>	PWM NOT switching			5	
		$0^{\circ}C < T_{J} < 85^{\circ}C$ , High-Z Mode				175	μA
IBATLEAK	Leakage current from BAT to the Supply	$0^{\circ}C < T_J < 85^{\circ}C, V_{BAT} = 4.2V, V_{USB}$	= V <sub>IN</sub> = 0V			5	μA
I <sub>BAT_HIZ</sub>	Battery discharge current in High Impedance mode, (BAT, SW, SYS)	$0^{\circ}C < T_{J} < 85^{\circ}C, V_{BAT} = 4.2V, V_{SUPP}$ SCL, SDA = 0 V or 1.8V, High-Z Mo			55	μA	
POWER-PAT	TH MANAGEMENT	1		1			
			bq24160, 1, 8	3.60	3.7	3.82	
V	System regulation voltage	Charge Enabled, V <sub>BAT</sub> < V <sub>MINSYS</sub>	bq24163	3.3	3.4	3.5	V
V <sub>SYS(REG)</sub>	System regulation voltage	Battery FET turned off (Charge Disa Charging Terminated)	abled, TS Fault or	VBATREG + 1.5%	VBATREG + 3.0%	VBATREG + 4.17%	v
		Charge enabled, V <sub>BAT</sub> < V <sub>MINSYS</sub> ,	bq24160, 1, 8	3.4	3.5	3.62	V
V <sub>MINSYS</sub>	Minimum system regulation voltage	Input current limit or VINDPM active	bq24163	3.1	3.2	3.3	V
V <sub>BSUP1</sub>	Enter supplement mode threshold	V <sub>BAT</sub> > 2.5V			VBAT –30mV		V
V <sub>BSUP2</sub>	Exit supplement mode threshold	V <sub>BAT</sub> > 2.5V			VBAT -10mV		V
ILIM(discharge)	Current limit, discharge or supplement mode	Current monitored in internal FET o	only.		7		А
t <sub>DGL(SC1)</sub>	Deglitch time, SYS short circuit during discharge or supplement mode	Measured from $(V_{BAT} - V_{SYS}) = 300$ impedance		250		μs	
t <sub>REC(SC1)</sub>	Recovery time, SYS short circuit during discharge or supplement mode			60		ms	
	Battery range for BGATE and supplement mode operation			2.5		4.5	V
BATTERY CI	HARGER	<u>+</u>					
		Measured from BAT to SYS,	YFF pkg		37	57	
R <sub>ON(BAT-SYS)</sub>	Internal battery charger MOSFET on-resistance	$V_{BAT} = 4.2V$	RGE pkg		50	70	mΩ
V	Charge Voltage	Operating in voltage regulation, Pro	grammable range	3.5		4.44	V
VBATREG	Voltage regulation accuracy			-1%		1%	
	Fast charge current range	$V_{BATSHRT} \le V_{BAT} < V_{BAT(REG)}$ program	nmable range	550		2500	mA
CHARGE	Fast charge current accuracy	0°C to 125°C		-10%		+10%	
V	Battery short circuit threshold	100mV Hysteresis	bq24161, 3, 8	1.9	2.0	2.1	V
VBATSHRT			bq24160, 1B	2.9	3.0	3.1	v
I <sub>BATSHRT</sub>	Battery short circuit current	V <sub>BAT</sub> < V <sub>BATSHRT</sub>			50		mA
t <sub>DGL(BATSHRT)</sub>	Deglitch time for battery short circuit to fastcharge transition				32		ms
	Termination charge current accuracy	I <sub>TERM</sub> = 50mA		-35%		+35%	
ITERM		I <sub>TERM</sub> ≥ 100mA		-15%		+15%	
t <sub>DGL(TERM)</sub>	Deglitch time for charge termination	Both rising and falling, 2mV overdrive	ve, $t_{RISE}$ , $t_{FALL}$ = 100ns		32		ms
V <sub>RCH</sub>	Recharge threshold voltage	Below V <sub>BATREG</sub>			120		mV
t <sub>DGL(RCH)</sub>	Deglitch time	VBAT falling below VRCH, tFALL=100ns			32		ms
V <sub>DETECT</sub>	Battery detection threshold	During battery detection source cycle			3.3		V
		During battery detection sink cycle			3.0		
IDETECT	Battery detection current before charge done (sink current)	Termination enabled (EN_TERM =	1)		2.5		mA
t <sub>DETECT</sub>	Battery detection time	Termination enabled (EN_TERM =	1)		250		ms
V <sub>IH</sub>	PSEL, CD Input high logic level			1.3			V
V <sub>IL</sub>	PSEL, CD Input low logic level					0.4	V

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## ELECTRICAL CHARACTERISTICS (Continued)

Circuit of Figure 23,  $V_{SUPPLY} = V_{USB}$  or  $V_{IN}$  (whichever is supplying the IC),  $V_{UVLO} < V_{SUPPLY} < V_{OVP}$  and  $V_{SUPPLY} > V_{BAT} + V_{SLP}$ ,  $T_J = -40^{\circ}C - 125^{\circ}C$  and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

	PARAMETER	TEST CONDI	TIONS	MIN	TYP	MAX	UNIT
INPUT CURF	RENT LIMITING						
			I <sub>USBLIM</sub> = USB100	90	95	100	
			I <sub>USBLIM</sub> = USB500	450	475	500	
	Input ourrent limit threshold (LISP input)	USB charge mode, V <sub>USB</sub> = 5V,	IUSBLIM = USB150	135	142.5	150	~ ^
IN_USB	Input current limit threshold (USB input)	DC Current pulled from SW	I <sub>USBLIM</sub> = USB900	800	850	900	mA
			I <sub>USBLIM</sub> = USB800	700	750	800	
			I <sub>USBLIM</sub> = 1.5A	1250	1400	1500	
	land a surrent limit thread and (IN insut)	IN charge mode, $V_{IN} = 5V$ ,	I <sub>INLIM</sub> = 1.5A	1.35	1.5	1.65	•
I <sub>IN_IN</sub>	Input current limit threshold (IN input)	DC Current pulled from SW	I <sub>INLIM</sub> = 2.5A	2.3	2.5	2.8	A
V <sub>IN_DPM</sub>	Input based DPM threshold range	Charge mode, programmable via	I <sup>2</sup> C, both inputs	4.2		4.76	V
	V <sub>IN DPM</sub> threshold accuracy			-2		+2%	
VDRV BIAS	REGULATOR	L					
V <sub>DRV</sub>	Internal bias regulator voltage	V <sub>SUPPLY</sub> > 5.45V		5	5.2	5.45	V
I <sub>DRV</sub>	DRV output current			10			mA
V <sub>DO_DRV</sub>	DRV Dropout voltage (V <sub>SUPPLY</sub> – V <sub>DRV</sub> )	I <sub>SUPPLY</sub> = 1A, V <sub>SUPPLY</sub> = 5V, I <sub>DRV</sub> =	10mA			450	mV
-	TPUT (STAT, INT)						
V <sub>OL</sub>	Low-level output saturation voltage	I <sub>O</sub> = 10mA, sink current				0.4	V
I <sub>IH</sub>	High-level leakage current	V <sub>STAT</sub> = V <sub>INT</sub> = 5V				1	μA
PROTECTIO		1					
V <sub>UVLO</sub>	IC active threshold voltage	V <sub>IN</sub> rising		3.6	3.8	4	V
V <sub>UVLO_HYS</sub>	IC active hysteresis	V <sub>IN</sub> falling from above V <sub>UVLO</sub>		120	150		mV
V <sub>SLP</sub>	Sleep-mode entry threshold, V <sub>SUPPLY</sub> -V <sub>BAT</sub>	2.0V ≤V <sub>BAT</sub> ≤V <sub>BATREG</sub> , V <sub>IN</sub> falling		0	40	100	mV
V <sub>SLP_EXIT</sub>	Sleep-mode exit hysteresis	2.0V ≤V <sub>BAT</sub> ≤V <sub>BATREG</sub>		40	100	175	mV
oer_extr	Deglitch time for supply rising above V <sub>SLP</sub> +V <sub>SLP EXIT</sub>	Rising voltage, 2mV over drive, t <sub>R</sub>	<sub>ISE</sub> = 100ns		30		ms
		<b>0 0 0 0 0</b>			V <sub>IN_DPM</sub>		
V <sub>BAD_SOURCE</sub>	Bad source detection threshold				– 80 mV		V
	Deglitch on bad source detection				32		ms
		USB, $V_{\text{USB}}$ Rising		6.3	6.5	6.7	
V <sub>OVP</sub>	Input supply OVP threshold voltage	IN, V <sub>IN</sub> Rising (bq24160/1/3)		10.3	10.5	10.7	V
		IN, V <sub>IN</sub> Rising (bq24168)		6.3	6.5	6.7	
V <sub>OVP(HYS)</sub>	V <sub>OVP</sub> hysteresis	Supply falling from V <sub>OVP</sub>			100		mV
V <sub>BOVP</sub>	Battery OVP threshold voltage	$V_{\text{BAT}}$ threshold over $V_{\text{OREG}}$ to turn	off charger during charge	1.025 × V <sub>BATREG</sub>	1.05 × V <sub>BATREG</sub>	1.075 × V <sub>BATREG</sub>	V
	V <sub>BOVP</sub> hysteresis	Lower limit for V <sub>BAT</sub> falling from at	pove V <sub>BOVP</sub>		1		% of V <sub>BATREG</sub>
t <sub>DGL(BOVP)</sub>	Battery OVP deglitch	BOVP fault shown in register once Buck converter shut down immed			1		ms
VBATUVLO	Battery undervoltage lockout threshold	V <sub>BAT</sub> rising, 100mV hysteresis			2.5		V
I <sub>LIMIT</sub>	Cycle-by-cycle current limit	V <sub>SYS</sub> shorted		4.1	4.9	5.6	А
T <sub>SHTDWN</sub>	Thermal trip				165		°C
	Thermal hysteresis				10		
T <sub>REG</sub>	Thermal regulation threshold	Charge current begins to cut off			120		°C
	Safety timer accuracy	(bq24160/1/3 Only)		-20%		20%	
PWM			L				
		$I_{IN\_LIMIT}$ = 500mA, Measured from	USB to PMIDU		95	175	-
	Internal top reverse blocking MOSFET on-resistance	$I_{\text{IN}}$ LIMIT = 500mA, Measured from IN to PMIDI			45	80	mΩ
	Internal top N-channel Switching MOSFET on-	Measured from PMIDU to SW			100	175	
	resistance	Measured from PMIDI to SW			65	110	mΩ
	Internal bottom N-channel MOSFET on-resistance	Measured from SW to PGND			65	115	mΩ
f <sub>osc</sub>	Oscillator frequency			1.35	1.50	1.65	MHz
D <sub>MAX</sub>	Maximum duty cycle				95%		
D <sub>MIN</sub>	Minimum duty cycle	1		0%			

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## **ELECTRICAL CHARACTERISTICS (Continued)**

Circuit of ,  $V_{SUPPLY} = V_{USB}$  or  $V_{IN}$  (whichever is supplying the IC),  $V_{UVLO} < V_{SUPPLY} < V_{OVP}$  and  $V_{SUPPLY} > V_{BAT} + V_{SLP}$ ,  $T_J = -40^{\circ}C - 125^{\circ}C$  and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
BATTERY-P	ACK NTC MONITOR						
V <sub>HOT</sub>	High temperature threshold	V <sub>TS</sub> falling	29.7	30	30.5	0()/	
V <sub>HYS(HOT)</sub>	Hysteresis on high threshold	V <sub>TS</sub> rising		1		%V <sub>DRV</sub>	
V <sub>WARM</sub>	High temperature threshold	V <sub>TS</sub> falling	37.9	38.3	39.6	0()(	
V <sub>HYS(WARM)</sub>	Hysteresis on high threshold	V <sub>TS</sub> rising		1		$%V_{DRV}$	
V <sub>COOL</sub>	Low temperature threshold	V <sub>TS</sub> falling	56	56.5	56.9	0/\/	
V <sub>HYS(COOL)</sub>	Hysteresis on low threshold	V <sub>TS</sub> rising		1		$%V_{DRV}$	
V <sub>COLD</sub>	Low temperature threshold	V <sub>TS</sub> falling	59.5	60	60.4	0()(	
V <sub>HYS(COLD)</sub>	Hysteresis on low threshold	V <sub>TS</sub> rising		1		$%V_{DRV}$	
TSOFF	TS Disable threshold	V <sub>TS</sub> rising, 2%V <sub>DRV</sub> hysteresis	70		73	%V <sub>DRV</sub>	
t <sub>DGL(TS)</sub>	Deglitch time on TS change			50		ms	
D+/D- DETE	CTION (bq24160)						
V <sub>D+_SRC</sub>	D+ Voltage Source		0.5	0.6	0.7	V	
I <sub>D+_SRC</sub>	D+ Connection Check Current Source		7		14	μA	
I <sub>DSINK</sub>	D- Current Sink		50	100	150	μA	
I <sub>D_LKG</sub>	Leakage Current into D+/D-	D-, switch open	-1		1	μA	
		D+, switch open	-1		1	μΑ	
V <sub>D+_LOW</sub>	D+ Low Comparator Threshold		0.8			V	
V <sub>DLOWdatref</sub>	D- Low Comparator Threshold		250		400	mV	
R <sub>DDWN</sub>	D- Pulldown for Connection Check		14.25		24.8	kΩ	
BATGD OPE	RATION		- H				
VBATGD	Good Battery threshold		3.6	3.8	3.9	V	
	Deglitch for good battery threshold	V <sub>BAT</sub> rising to HIGH-Z mode, DEFAULT Mode Only		32		ms	
I <sup>2</sup> C COMPAT	TIBLE INTERFACE		·				
V <sub>IH</sub>	Input low threshold level	V <sub>PULL-UP</sub> = 1.8V, SDA and SCL	1.3			V	
VIL	Input low threshold level	V <sub>PULL-UP</sub> = 1.8V, SDA and SCL			0.4	V	
V <sub>OL</sub>	Output low threshold level	I <sub>L</sub> = 10mA, sink current			0.4	V	
I <sub>BIAS</sub>	High-Level leakage current	V <sub>PULL-UP</sub> = 1.8V, SDA and SCL		1		μA	
t <sub>WATCHDOG</sub>	Watchdog timer timeout	(bq24160/1/3 Only)	30			s	

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#### **BLOCK DIAGRAM**



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#### **PIN CONFIGURATION**







Figure 2. 49-Ball 2.8mm x 2.8mm WCSP (YFF)

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#### **PIN FUNCTIONS**

PIN		NO. 160, 3	PIN bq24161		1/0	DESCRIPTION	
NAME	YFF	RGE	YFF	RGE	I/O DESCRIPTION		
BAT	G1-G4	11, 12	G1-G4	11, 12	I/O	<b>Battery Connection</b> – Connect to the positive terminal of the battery. Additionally, bypass BAT to GND with at least a $1\mu$ F capacitor.	
BGATE	F5	10	F5	10	0	<ul> <li>External Discharge MOSFET Gate Connection – BGATE drives an external P-Channel MOSFET to provide a very low-resistance discharge path. Connect BGATE to the gate of the external MOSFET. BGATE is low during high impedance mode and when no input is connect</li> <li>High Side MOSFET Gate Driver Supply – Connect a 0.01µF ceramic capacitor (voltage ratio)</li> </ul>	
BOOT	E7	19	E7	19	I	<ul> <li>High Side MOSFET Gate Driver Supply – Connect a 0.01µF ceramic capacitor (voltage rations &gt; 10V) from BOOT to SW to supply the gate drive for the high side MOSFETs.</li> <li>IC Hardware Disable Input – Drive CD high to place the bq2416x in high-z mode. Drive CD</li> </ul>	
CD	E4	24	E4	24	I	IC Hardware Disable Input – Drive CD high to place the bq2416x in high-z mode. Drive CD low for normal operation. Do not leave CD unconnected.	
D+	E2	2	—	—	I	D+ and D- Connections for USB Input Adapter Detection – When a charge cycle is initiated	
D-	E3	1	—	—	I	by the USB input, and a short is detected between D+ and D-, the USB input current limit i to 1.5A. If a short is not detected, the USB100 mode is selected. The D+/D- detection has effect on the IN input.	
DRV	F7	6	F7	6	0	<b>Gate Drive Supply</b> – DRV is the bias supply for the gate drive of the internal MOSFETs. Bypass DRV to PGND with a 1µF ceramic capacitor. DRV may be used to drive external loads up to 10mA. DRV is active whenever the input is connected and $V_{SUPPLY} > V_{UVLO}$ and $V_{SUPPLY} > (V_{BAT} + V_{SLP})$	
IN	A1- A4	21	A1- A4	21	I	<b>Input power supply</b> – IN is connected to the external DC supply (AC adapter or alternate power source). Bypass IN to PGND with at least a $1\mu$ F ceramic capacitor.	
INT	F6	7	F6	7	0	<b>Status Output</b> – INT is an open-drain output that signals charging status and fault interrupts. INT pulls low during charging. INT is high impedance when charging is complete or the charger is disabled. When a fault occurs, a 128µs pulse is sent out as an interrupt for the host. INT is enabled/disabled using the EN_STAT bit in the control register. Connect INT to a logic rail through a 100k $\Omega$ resistor to communicate with the host processor.	
PGND	D1-D7, E1, G7	5, 15, 16, 17	D1-D7, E1, G7	5, 15, 16, 17	—	Ground terminal – Connect to the thermal pad (for QFN only) and the ground plane of the circuit.	
PMIDI	B1-B4	20	B1-B4	20	0	<b>Reverse Blocking MOSFET and High Side MOSFET Connection Point for High Power</b> <b>Input</b> – Bypass PMIDI to GND with at least a 4.7µF ceramic capacitor. Use caution when connecting an external load to PMIDI. The PMIDI output is not current limited. Any short on PMIDI will damage the IC.	
PMIDU	B5-B7	23	B5-B7	23	0	Reverse Blocking MOSFET and High Side MOSFET Connection Point for USB Input – Bypass PMIDU to GND with at least a $4.7\mu$ F ceramic capacitor. Use caution when connecting an external load to PMIDU. The PMIDU output is not current limited. Any short on PMIDU will damage the IC.	
PSEL	_	_	E2	2		<b>USB Source Detection Input</b> – Drive PSEL high to indicate that a USB source is connected to the USB input. When PSEL is high, the IC starts up with a 100mA (bq24161/8) or 500mA (bq24161B) input current limit for USB. Drive PSEL low to indicate that an AC Adapter is connected to the USB input. When PSEL is low, the IC starts up with a 1.5A input current limit for USB. PSEL has no effect on the IN input. Do not leave PSEL unconnected.	
SCL	E6	3	E6	3	I	I <sup>2</sup> C Interface Clock – Connect SCL to the logic rail through a 10kΩ resistor.	
SDA	E5	4	E5	4	I/O	I <sup>2</sup> C Interface Data – Connect SDA to the logic rail through a 10kΩ resistor.	
STAT	G6	8	G6	8	0	<b>Status Output</b> – STAT is an open-drain output that signals charging status and fault interrupts. STAT pulls low during charging. STAT is high impedance when charging is complete or the charger is disabled. When a fault occurs, a 128µs pulse is sent out as an interrupt for the host. STAT is enabled /disabled using the EN_STAT bit in the control register. Pull STAT up to a logic rail thruogh an LED for visual indication or through a 10k $\Omega$ resistor to communicate with the host processor.	
SW	C1-C7	18	C1-C7	18	0	Inductor Connection – Connect to the switched side of the external inductor.	
SYS	F1-F4	13, 14	F1-F4	13,14	Ι	System Voltage Sense and Charger FET Connection – Connect SYS to the system output at the output bulk capacitors. Bypass SYS locally with at least $10\mu$ F. A $47\mu$ F bypass capacitor is recommended for optimal transient response.	
TS	G5	9	G5	9	I	<ul> <li>Battery Pack NTC Monitor – Connect TS to the center tap of a resistor divider from DRV to GND. The NTC is connected from TS to GND. The TS function provides 4 thresholds for JEIT compatibility (160, 161B, 163, 168 only). TS faults are reported by the I<sup>2</sup>C interface. See the NTC Monitor section for more details on operation and selecting the resistor values. Connect to DRV to disable the TS function.</li> </ul>	
USB	A5-A7	22	A5-A7	22	I	<b>USB Input Power Supply</b> – USB is connected to the external DC supply (AC adapter or USB port). Bypass USB to PGND with at least a $1\mu$ F ceramic capacitor.	
Thermal Pad	-	Pad	_	Pad	_	There is an internal electrical connection between the exposed thermal pad and the PGND pin of the device. The thermal pad must be connected to the same potential as the PGND pin on the printed circuit board. Do not use the thermal pad as the primary ground input for the device. PGND pin must be connected to ground at all times.	



# TYPICAL APPLICATION CIRCUIT



Figure 3. bq24160, Shown with no External Discharge FET, PA Connected to Battery



Figure 4. – bq24161, Shown with External Discharge FET, PA Connected to System for GSM Call Support with a Deeply Discharged or No Battery

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V<sub>USB</sub>

 $V_{SYS}$ 

 $\mathsf{V}_{\mathsf{BAT}}$ 

 $I_{\text{BAT}}$ 

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Conditions: USB500, 925mA Charge Setting

**USB Plug-In with Battery Connected** 

20 ms/div

Figure 5.

**IN Plug-in with Battery Connected** 5 V/div VIN 1 V/div 500 mA/div V<sub>SYS</sub> V<sub>BAT</sub>























# **TYPICAL CHARACTERISTICS**



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10 ms/div

Conditions: MINSYS Operation, USB500, 200mA - 1400mA Load Step on SYS



















#### Figure 14.



Figure 16.

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#### **TYPICAL CHARACTERISTICS (continued)**

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**ISTRUMENTS** 

EXAS

6.5V OVP Threshold vs. Temperature

1.5

Battery Voltage (V)

Figure 21.

2

2.5

3

G009

0.05

0

0.5

14





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#### DETAILED DESCRIPTION

The bq24160/bq24160A/bq24161/bq24161B/bq24163/bq24168 are highly integrated single cell Li-Ion battery chargers and system power path management devices targeted for space-limited, portable applications with high capacity batteries. The dual-input, single-cell charger operates from either a USB port or alternate power source (i.e. wall adapter or wireless power input) for a versatile solution.

The power path management feature allows the bq2416x to power the system from a high efficiency DC-to-DC converter while simultaneously and independently charging the battery. The charger monitors the battery current at all times and reduces the charge current when the system load requires current above the input current limit. This allows proper charge termination and enables the system to run with a defective or absent battery pack. Additionally, this enables instant system turn-on even with a totally discharged battery or no battery. The power-path management architecture also permits the battery to supplement the system current requirements when the adapter cannot deliver the peak system currents. This enables the use of a smaller adapter. The 2.5 A current capability allows for GSM phone calls as soon as the adapter is plugged in regardless of the battery voltage. The charge parameters are programmable using the  $I^2C$  interface.

#### CHARGE MODE OPERATION

#### Charge Profile

The internal battery MOSFET is used to charge the battery. When the battery is above the MINSYS votlage, the the internal FET is on to maximize efficiency and the PWM converter regulates the charge current into the battery. When battery is less than MINSYS, the SYS is regulated to  $V_{SYS(REG)}$  and battery is charged using the battery FET to regulate the charge current. There are 5 loops that influence the charge current:

- Constant current loop (CC)
- Constant voltage loop (CV)
- Thermal-regulation loop
- Minimum system-voltage loop (MINSYS)
- Input-voltage dynamic power-management loop (V<sub>IN</sub>-DPM)

During the charging process, all five loops are enabled and the one that is dominant takes control. The bq2416x supports a precision Li-lon or Li-Polymer charging system for single-cell applications. The Dynamic Power Path Management (DPPM) feature regulates the system voltage to a minimum of V<sub>MINSYS</sub>, so that startup is enabled even for a missing or deeply discharged battery. Figure 22 shows a typical charge profile including the minimum system output voltage feature.

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Figure 22. Typical bq2416x Charging Profile

#### PWM Controller in Charge Mode

The bq2416x provides an integrated, fixed-frequency 1.5MHz voltage-mode controller to power the system and supply the charge current. The voltage loop is internally compensated and provides enough phase margin for stable operation, allowing the use of small ceramic capacitors with very low ESR.

The input scheme for the bq2416x prevents battery discharge when the supply voltages are lower than VBAT and also isolates the two inputs from each other. The high-side N-MOSFET (Q1/Q2) switches to control the power delivered to the output. The DRV LDO provides a supply for the gate drive for the low side MOSFET, while a bootstrap circuit (BST) with an external bootstrap capacitor is used to boost up the gate drive voltage for Q1 and Q2.

Both inputs are protected by a cycle-by-cycle current limit that is sensed through the high-side MOSFETs for Q1 and Q2. The threshold for the current limit is set to a nominal 5A peak current. The inputs also utilize an input current limit that limits the current from the power source.

#### **Battery Charging Process**

When the battery is deeply discharged or shorted ( $V_{BAT} < V_{BATSHRT}$ ), the bq2416x applies I<sub>BATSHRT</sub> to close the pack protector switch and bring the battery voltage up to acceptable charging levels. During this time, the battery FET is linearly regulated and the system output is regulated to  $V_{SYS(REG)}$ . Once the battery rises above  $V_{BATSHRT}$ , the charge current is regulated to the value set in the I<sup>2</sup>C register. The battery FET is linearly regulated to maintain the system voltage at  $V_{SYS(REG)}$ . Under normal conditions, the time spent in this region is a very short percentage of the total charging time, so the linear regulation of the charge current does not affect the overall charging efficiency for very long. If the die temperature does rise, the thermal regulation circuit reduces the charge current to maintain a die temperature less than 120°C. If the current limit for the SYS output is reached (limited by the input current limit, or  $V_{IN_DPM}$ ), the SYS output drops to the  $V_{MINSYS}$  output voltage. When this happens, the charge current is reduced to provide the system with all the current that is needed while maintaining the minimum system voltage. If the charge current is reduced to 0mA, pulling further current from SYS causes the output to fall to the battery voltage and enter supplement mode. (See the *Dynamic Power Path Management* section for more details.)

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Once the battery is charged enough so that the system voltage begins to rise above  $V_{SYS(REG)}$ , the battery FET is turned on fully and the battery is charged with the full programmed charge current set by the I<sup>2</sup>C interface, I<sub>CHARGE</sub>. The slew rate for the fast-charge current is controlled to minimize current and voltage overshoot during transients. The charge current is regulated to I<sub>CHARGE</sub> until the battery is charged to the regulation voltage. Once the battery voltage is close to the regulation voltage, V<sub>BATREG</sub>, the charge current is tapered down as shown in Figure 22 while the SYS output remains connected to the battery. The voltage-regulation feedback occurs by monitoring the battery-pack voltage between the BAT and PGND pins. The bq2416x is a fixed single-cell voltage version, with adjustable regulation voltage (3.5V to 4.44V), programmed using the I<sup>2</sup>C interface.

The bq2416x monitors the charging current during the voltage-regulation phase. Once the termination threshold,  $I_{\text{TERM}}$ , is detected and the battery voltage is above the recharge threshold, the bq2416x terminates charge, turns off the battery charging FET and enters battery detection. The system output is regulated to the V<sub>SYS(REG)</sub> and supports the full current available from the input and the battery supplement mode is available. (See the *Dynamic Power Path Management* section for more details.) The termination current level is programmable. To disable the charge current termination, the host sets the charge termination bit (TE) of charge control register to 0, refer to  $I^2C$  section for details.

A new charge cycle is initiated when one of the following conditions is detected:

- 1. The battery voltage falls below the  $V_{BATREG}$ - $V_{RCH}$  threshold.
- 2. V<sub>SUPPLY</sub> toggle
- 3. CE bit toggle or RESET bit is set
- 4. HI-Z bit toggle

#### **Battery Detection**

When termination conditions are met, a battery detection cycle is started. During battery detection,  $I_{DETECT}$  is pulled from  $V_{BAT}$  for  $t_{DETECT}$  to verify there is a battery. If the battery voltage remains above  $V_{DETECT}$  for the full duration of  $t_{DETECT}$ , a battery is determined to present and the IC enters "Charge Done". If  $V_{BAT}$  falls below  $V_{DETECT}$ , a "Battery Not Present" fault is signaled and battery detection continues. The next cycle of battery detection, the bq2416x turns on  $I_{BATSHORT}$  for  $t_{DETECT}$ . If  $V_{BAT}$  rises to  $V_{DETECT}$ , the current source is turned offand after  $t_{DETECT}$ , the battery detection continues through another current sink cycle. Battery detection continues

until charge is disabled or a battery is detected. Once a battery is detected, the fault status clears and a new charge cycle begins. Battery detection is not run when termination is disabled.

#### **Dynamic Power Path Management (DPPM)**

The bq2416x features a SYS output that powers the external system load connected to the battery. This output is active whenever a source is connected to IN, USB or BAT. The following sections discuss the behavior of SYS with a source connected to the supply or a battery source only.

## Input Source Connected

When a valid input source is connected, the buck converter turns on to power the load on SYS. The STAT/INT pin outputs a 128µs interrupt pulse to alert the host that an input has been connected. The FAULT bits indicate a normal condition, and the Supply Status register indicates that a new supply is connected. The  $\overline{CE}$  bit (bit 1) in the control register (0x02) indicates whether a charge cycle is initiated. By default, the bq2416x ( $\overline{CE}$ =0) enables a charge cycle when a valid input source is connected. When the  $\overline{CE}$  bit is '1' and a valid input source is connected, the battery FET is turned off and the SYS output is regulated to the V<sub>SYS(REG)</sub> programmed by the V<sub>BATREG</sub> threshold in the l<sup>2</sup>C register. A charge cycle is initiated when the  $\overline{CE}$  bit is written to a 0 value (cleared).

When the  $\overline{CE}$  bit is a 0 and a valid source is connected to IN or USB, the buck converter starts up and a charge cycle is initiated. When V<sub>BAT</sub> is high enough that V<sub>SYS</sub> > V<sub>SYS(REG)</sub>, the battery FET is turned on and the SYS output is connected to BAT. If the SYS voltage falls to V<sub>SYS(REG)</sub>, it is regulated to that point to maintain the system output even with a deeply discharged or absent battery. In this mode, the SYS output voltage is regulated by the buck converter and the battery FET linearly regulates the charge current into the battery. The current from the supply is shared between charging the battery and powering the system load at SYS. The dynamic power-

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path management (DPPM) circuitry of the bq2416x monitors the current limits continuously, and if the SYS voltage falls to the V<sub>MINSYS</sub> voltage, it adjusts charge current to maintain the minimum system voltage and supply the load on SYS. If the charge current is reduced to zero and the load increases further, the bq2416x enters battery-supplement mode. During supplement mode, the battery FET is turned on and the battery supplements the system load.



Figure 23. Example DPPM Response (V<sub>Supply</sub>=5V, V<sub>BAT</sub> = 3.1V, 1.5A Input current limit)

 $V_{BAT(REG)}$  should never be programmed less than  $V_{BAT}$ . If the battery is ever 5% above the regulation threshold, the battery OVP circuit shuts the PWM converter of immediately and the battery FET is turned on to discharge the battery to safe operating levels. If the battery OVP condition exists for the 1ms deglitch, a battery OVP fault is reported in the I<sup>2</sup>C status registers. The battery OVP fault is cleared when the battery voltage discharges below  $V_{RCH}$  or if the IC enters hi-impedance mode (HZ\_MODE=1 or CD=1). Always write bq2416x to high impedance mode before changing  $V_{BATREG}$  to clear BOVP condition to ensure proper operation.

## **Battery Only Connected**

When a battery voltage less than  $V_{BATUVLO}$  is connected with no input source, the battery FET is turned on similar to supplement mode. In this mode, the current is not regulated; however, there is a short circuit current limit. If the short circuit limit is reached, the battery FET is turned off for the deglitch time ( $t_{DGL(SC1)}$ ). After the recovery time ( $t_{REC(SC1)}$ ), the battery FET is turned on to test and see if the short has been removed. If it has not, the FET turns off and the process repeats until the short is removed. This process is to protect the internal FET from over current. If an external FET is used for discharge, the body diode prevents the load on SYS from being disconnected from the battery. If the battery voltage is less than  $V_{BATUVLO}$ , the battery FET (Q4) remains off and BAT is high-impedance. This prevents further discharging of deeply-discharged batteries.

## **Battery Discharge FET (BGATE)**

The bq2416x contains a MOSFET driver to drive the gate of an external discharge FET between the battery and the system output. This external FET provides a low impedance path when supplying the system from the battery. Connect BGATE to the gate of the external discharge MOSFET. BGATE is on under the following conditions:



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- 1. No input supply connected.
- 2. HZ\_MODE = 1
- 3. CD pin connected high

## DEFAULT Mode

DEFAULT mode is used when I<sup>2</sup>C communication is not available. DEFAULT mode is entered in the following situations:

- 1. When the charger is enabled and  $V_{BAT}$ <  $V_{BATGD}$  before I<sup>2</sup>C communication is established
- 2. When the watchdog timer expires without a reset from the  $I^2C$  interface and the safety timer has not expired.
- 3. When the device comes out of any fault condition (sleep mode, OVP, faulty adapter mode, etc.) before I<sup>2</sup>C communication is established

In DEFAULT mode, the  $l^2C$  registers are reset to the default values. The 27-minute safety timer (no timer for bq24168) is reset and starts when DEFAULT mode is entered. The default value for VBATREG is 3.6V, and the default value for  $l_{CHARGE}$  is 1A. The input current limit for the IN input is set to 1.5A. The input current limit for the USB input is determined by the D+/D- detection (bq24160/3) or PSEL (bq24161/1B/8). PSEL and D+/D- detection have no effect on the IN input. Default mode is exited by programming the  $l^2C$  interface. Once  $l^2C$  communication is established, PSEL has no effect on the USB input. Note that if termination is enabled and charging has terminated, a new charge cycle is NOT initiated when entering DEFAULT mode.



#### Safety Timer and Watchdog Timer (bq24160/ bq24161/ bq24161B/ bq24163 only)

At the beginning of charging process, the bq24160/1/1B/3 starts the safety timer. This timer is active during the entire charging process. If charging has not terminated before the safety timer expires, charging is disabled, the charge parameters are reset to the default values and the CE bit is written to a "1". The length of the safety timer is selectable using the I<sup>2</sup>C interface. A single 128µs pulse is sent on the STAT and INT outputs and the STATx bits of the status registers are updated in the I<sup>2</sup>C. In DEFAULT mode, the safety timer can be reset and a new charge initiated by removing/inserting the input supply or toggling the CD pin. In HOST mode, the CE bit is set to a '1' when the safety timer expires. The CE bit must be cleared to a '0' in order to resume charging and clear the safety timer fault. The safety timer duration is selectable using the TMR\_X bits in the Safety Timer Register/ NTC Monitor register. Changing the safety timer duration resets the safety timer. This function prevents continuous charging of a defective battery.

In addition to the safety timer, the bq24160/1/1B/3 contain a watchdog timer that monitors the host through the  $I^2C$  interface. Once a read/write is performed on the  $I^2C$  interface, a 30-second timer ( $t_{WATCHDOG}$ ) is started. The 30-second timer is reset by the host using the  $I^2C$  interface. This is done by writing a "1" to the reset bit (TMR\_RST) in the control register. The TMR\_RST bit is automatically set to "0" when the 30-second timer is reset. This process continues until the battery is fully charged or the safety timer expires. If the 30-second timer expires, the IC enters DEFAULT mode where the default register values are loaded, the safety timer restarts at 27 minutes and charging continues. The  $I^2C$  may be accessed again to reinitialize the desired values and restart the watchdog timer. The watchdog timer flow chart is shown in Figure 24.



Figure 24. The Watchdog Timer Flow Chart for bq2416x



## D+, D– Based Adapter Detection for the USB Input (D+, D–, bq24160/0A/3)

The bq24160/0A/3 contain a D+, D– based adapter detection circuit that is used to program the input current limit for the USB input during DEFAULT mode. D+, D– detection is only performed in DEFAULT mode unless forced by the D+, D–\_EN bit in host mode.

By default the USB input current limit is set to 100mA. When USB is asserted the bq24160/0A/3 performs a charger source identification to determine if it is connected to an SDP (USB port) or CDP/DCP (dedicated charger). When the detection is initated, the first step is the connection detection as described in BC1.2. This step detects when the D+, D- lines are connected to the bq24160/3. Once this connection is made, the circuit moves to the Primary Detection. If the connection detection has not completed within 500ms, the D+, D- detection selects 100mA for the unknown input source.

The primary detection complies with the method described in BC1.2. During primary detection, the D+, D- lines are tested to determine if the port is an SDP or CDP/DCP. If a CDP/DCP is detected the input current limit is increased to 1.5A, if an SDP is detected the current limit remains at 100mA, until changed via the I<sup>2</sup>C interface. Secondary detection is not performed.

Automatic detection is performed only if  $V_{D+}$  and  $V_{D-}$  are less than 0.6V to avoid interfering with the USB transceiver which may also perform D+, D– detection when the system is running normally. However, D+, D– can be initiated at any time by the host by setting the D+, D– EN bit in the Control/Battery Voltage Register to 1. After detection is complete the D+, D– EN bit is automatically reset to 0 and the detection circuitry is disconnected from the D+, D– pins to avoid interference with USB data transfer.

When a command is written to change the input current limit in the  $I^2C$ , this overrides the current limit selected by D+/D- detection. D+, D- detection has no effect on the IN input.

#### USB Input Current Limit Selector Input (PSEL, bq24161/ 161B/ 168 only)

The bq24161, bq24161B, and bq24168 contain a PSEL input that is used to program the input current limit for USB during DEFAULT mode. Drive PSEL high to indicate that a USB source is connected to the USB input and program the 100mA (bq24161/8) or 500mA (bq24161B) current limit for USB. Drive PSEL low to indicate that an AC Adapter is connected to the USB input. When PSEL is low, the IC starts up with a 1.5A current limit for USB. PSEL has no effect on the IN input. Once an I<sup>2</sup>C write is done, the PSEL has no effect on the input current limit until the watchdog timer expires.

#### Hardware Chip Disable Input (CD)

The bq2416x contains a CD input that is used to disable the IC and place the bq2416x into high-impedance mode. Drive CD low to enable charge and enter normal operation. Drive CD high to disable charge and place the bq2416x into high-impedance mode. Driving CD high during DEFAULT mode resets the safety timer. Driving CD high during HOST mode resets the safety timer and places the bq2416x into high impedance mode. The CD pin has precedence over the I<sup>2</sup>C control.

## LDO Output (DRV)

The bq2416x contains a linear regulator (DRV) that is used to supply the internal MOSFET drivers and other circuitry. Additionally, DRV supplies up to 10mA external loads to power the STAT LED or the USB transceiver circuitry. The maximum value of the DRV output is 5.45V; ideal for protecting voltage sensitive USB circuits from high voltage fluctuations in the supply. The LDO is on whenever a supply is connected to the IN or USB inputs of the bq2416x. The DRV is disabled under the following conditions:

- 1. V<sub>SUPPLY</sub> < UVLO
- 2. V<sub>SUPPLY</sub> < V<sub>SLP</sub>
- 3. Thermal Shutdown



#### External NTC Monitoring (TS)

The I<sup>2</sup>C interface allows the user to easily implement the JEITA standard for systems where the battery pack thermistor is monitored by the host. Additionally, the bq2416x provides a flexible, voltage based TS input for monitoring the battery pack NTC thermistor. The voltage at TS is monitored to determine that the battery is at a safe temperature during charging. The bq24160, bq24160A, bq24161B, bq24163, and bq24168 enable the user to easily implement the JEITA standard for charging temperature while the bq24161 only monitors the hot and cold cutoff temperatures and leaves the JEITA control to the host. The JEITA specification is shown in.



Figure 25. Charge Current During TS Conditions

To satisfy the JEITA requirements, four temperature thresholds are monitored; the cold battery threshold ( $T_{NTC} < 0^{\circ}C$ ), the cool battery threshold ( $0^{\circ}C < T_{NTC} < 10^{\circ}C$ ), the warm battery threshold ( $45^{\circ}C < T_{NTC} < L60^{\circ}C$ ) and the hot battery threshold ( $T_{NTC} > 60^{\circ}C$ ). These temperatures correspond to the V<sub>COLD</sub>, V<sub>COLD</sub>, V<sub>WARM</sub>, and V<sub>HOT</sub> thresholds. Charging is suspended and timers are suspended when V<sub>TS</sub> < V<sub>HOT</sub> or V<sub>TS</sub> > V<sub>COLD</sub>. When V<sub>WARM</sub> > V<sub>TS</sub> > V<sub>HOT</sub>, the battery regulation voltage is reduced by 140mV from the programmed regulation threshold. When V<sub>COLD</sub> > V<sub>TS</sub> > V<sub>COOL</sub>, the charging current is reduced to half of the programmed charge current.

The TS function is voltage based for maximum flexibility. Connect a resistor divider from DRV to GND with TS connected to the center tap to set the threshold. The connections are shown in Figure 31. The resistor values are calculated using the following equations:

$$RLO = \frac{V_{DRV} \times RCOLD \times RHOT \times \left[\frac{1}{V_{COLD}} - \frac{1}{V_{HOT}}\right]}{RHOT \times \left[\frac{V_{DRV}}{V_{HOT}} - 1\right] - RCOLD \times \left[\frac{V_{DRV}}{V_{COLD}} - 1\right]}$$
(1)  
$$RHI = \frac{\frac{V_{DRV}}{V_{COLD}} - 1}{\frac{1}{RLO} + \frac{1}{RCOLD}}$$
(2)  
Where:

 $V_{COLD} = 0.60 \times V_{DRV}$  $V_{HOT} = 0.30 \times V_{DRV}$ 



Where R<sub>HOT</sub> is the NTC resistance at the hot temperature and R<sub>COLD</sub> is the NTC resistance at cold temperature.

For the bq24160, bq24161B, bq24163, and bq24168, the WARM and COOL thresholds are not independently programmable. The COOL and WARM NTC resistances for a selected resistor divider are calculated using the following equations:

$$RCOOL = \frac{RLO \times 0.564 \times RHI}{RLO - RLO \times 0.564 - RHI \times 0.564}$$
(3)  

$$RWARM = \frac{RLO \times 0.383 \times RHI}{RLO - RLO \times 0.383 - RHI \times 0.383}$$
(4)  

$$\boxed{\begin{array}{c} V_{BAT(REG)} \ 1 \times Charge/ \\ DISABLE \ -140 \ mV \ 0.5 \times Charge \ V_{DRV} \\ \hline \end{array}}$$



Figure 26. TS Circuit

## **Thermal Regulation and Protection**

During the charging process, to prevent chip overheating, the bq2416x monitors the junction temperature,  $T_J$ , of the die and begins to taper down the charge current once  $T_J$  reaches the thermal regulation threshold,  $T_{REG}$ . The charge current is reduced to zero when the junction temperature increases about 10°C above  $T_{REG}$ . Once the charge current is reduced, the system current is reduced while the battery supplements the load to supply the system. This may cause a thermal shutdown of the bq2416x if the die temperature rises too high. At any state, if  $T_J$  exceeds  $T_{SHTDWN}$ , the bq2416x suspends charging and disables the buck converter. During thermal shutdown mode, the buck converter is turned off, all timers are suspended, and a single 128µs pulse is sent on the STAT and INT outputs and the STATx and FAULT\_x bits of the status registers are updated in the l<sup>2</sup>C. A new charging cycle begins when  $T_J$  falls below  $T_{SHTDWN}$  by approximately 10°C.

#### Input Voltage Protection in Charge Mode

#### Sleep Mode

The bq2416x enters the low-power sleep mode if the voltage on  $V_{SUPPLY}$  falls below the sleep-mode entry threshold,  $V_{BAT}+V_{SLP}$ , and  $V_{SUPPLY}$  is higher than the undervoltage lockout threshold,  $V_{UVLO}$ . This feature prevents draining the battery during the absence of  $V_{SUPPLY}$ . When  $V_{SUPPLY} < V_{BAT} + V_{SLP}$ , the bq2416x turns off the PWM converter, turns the battery FET on and drives BGATE to GND, sends a single 128µs pulse on the STAT and INT outputs and updates the STATx and FAULT\_x bits in the status registers. Once  $V_{SUPPLY} > V_{BAT} + V_{SLP}$ , the STATx and FAULT\_x bits are cleared and the device initiates a new charge cycle.



#### Input Voltage Based DPM

During normal charging process, if the input power source is not able to support the programmed or default charging current, the supply voltage decreases. Once the supply drops to  $V_{IN_DPM}$  (default 4.2V for both inputs), the input current limit is reduced to prevent further supply droop. When the IC enters this mode, the charge current is lower than the set value and the DPM\_STATUS bit is set (Bit 5 in Register 05H). This feature provides IC compatibility with adapters with different current capabilities without a hardware change. Figure 27 shows the  $V_{IN_DPM}$  behavior to a current-limited source. In this figure the input source has a 750mA current limit and the charging is set to 750mA. The SYS load is then increased to 1.2A.



Figure 27. bq24160 V<sub>IN-</sub>DPM

#### **Bad Source Detection**

When a source is connected to IN or USB, the bq2416x runs a Bad Source Detection procedure to determine if the source is strong enough to provide some current to charge the battery. A current sink is turned on (30mA for USB input, 75mA for the IN input) for 32ms. If the source is valid after the 32ms ( $V_{BADSOURCE} < V_{SUPPLY} < V_{OVP}$ ), the buck converter starts up and normal operation continues. If the supply voltage falls below  $V_{BAD_SOURCE}$  during the detection, the current sink shuts off for two seconds and then retries, a single 128µs pulse is sent on the STAT and INT outputs and the STATx and FAULT\_x bits of the status registers and the battery/supply status registers are updated. The detected after the detection time. If during normal operation the source falls to  $V_{BAD_SOURCE}$ , the bq2416x turns off the PWM converter, turns the battery FET on, sends a single 128µs pulse is sent on the STAT and INT outputs and the STATx and FAULT\_x bits of the status registers, and the battery/supply status registers are updated. Once a good source is detected, the STATx and FAULT\_x bits are cleared and the device returns to normal operation.

If two supplies are connected, the supply with precedence is checked first. If the supply detection fails once, the device switches to the other supply for two seconds and then retries. This allows the priority supply to settle if the connection was jittery or the supply ramp was too slow to pass detection. If the priority supply fails the detection a second time, it is locked out and lower priority supply is used. Once the bad supply is locked out, it remains locked out until the supply voltage falls below UVLO. This prevents continuously switching between a weak supply and a good supply.



#### **Input Overvoltage Protection**

The built-in input overvoltage protection to protect the device and other downstream components against damage from overvoltage on the input supply (Voltage from  $V_{USB}$  or  $V_{IN}$  to PGND). During normal operation, if  $V_{SUPPLY} > V_{OVP}$ , the bq2416x turns off the PWM converter, turns the battery FET and BGATE on, sends a single 128µs pulse is sent on the STAT and INT outputs and the STATx and FAULT\_x bits of the status registers and the battery/supply status registers are updated. Once the OVP fault is removed, the STATx and FAULT\_x bits are cleared and the device returns to normal operation.

To allow operation with some unregulated adapters, the OVP circuit is not active during Bad Source Detection. This provides some time for the current sink to pull the unregulated adapter down into an acceptable range. If the adapter voltage is high at the end of the detection, the startup of the PWM converter does not occur. The OVP circuit is active during normal operation, so if the system standby current plus the charge current is not enough to pull down the source, operation is suspended.

## Charge Status Outputs (STAT, INT)

The STAT output is used to indicate operation conditions for bq2416x. STAT is pulled low during charging when EN\_STAT bit in the control register (0x02h) is set to "1". When charge is complete or disabled, STAT is high impedance. When a fault occurs, a 128-µs pulse (interrupt) is sent out to notify the host. The status of STAT during different operation conditions is summarized in Table 1. STAT drives an LED for visual indication or can be connected to the logic rail for host communication. The EN\_STAT bit in the control register (00H) is used to enable/disable the charge status for STAT. The interrupt pulses are unaffected by EN\_STAT and will always be shown. The INT output is identical to STAT and is used to interface with a low voltage host processor.

Charge State	STAT and INT behavior
Charge in progress and EN_STAT=1	Low
Other normal conditions	High-Impedance
Status Changes: Supply Status Change (plug in or removal), safety timer fault, watchdog expiration, sleep mode, battery temperature fault (TS), battery fault (OVP or absent), thermal shutdown	128-µs pulse, then High Impedance

## Good Battery Monitor

The bq2416x contains a good battery monitor circuit that places the bq2416x into high-z mode if the battery voltage is above the BATGD threshold while in DEFAULT mode. This function is used to enable compliance to the battery charging standard that prevents charging from an un-enumerated USB host while the battery is above the good battery threshold. If the bq2416x is in HOST mode, it is assumed that USB host has been enumerated and the good battery circuit has no effect on charging.

## SERIAL INTERFACE DESCRIPTION

The bq2416x uses an I<sup>2</sup>C-compatible interface to program charge parameters. I<sup>2</sup>C is a 2-wire serial interface developed by Philips Semiconductor (see I<sup>2</sup>C-Bus Specification, Version 2.1, January 2000). The bus consists of a data line (SDA) and a clock line (SCL) with pull-up structures. When the bus is idle, both SDA and SCL lines are pulled high. All I<sup>2</sup>C-compatible devices connect to the I<sup>2</sup>C bus through open drain I/O pins, SDA and SCL. A master device, usually a microcontroller or a digital signal processor, controls the bus. The master is responsible for generating the SCL signal and device addresses. The master also generates specific conditions that indicate the START and STOP of data transfer. A slave device receives and/or transmits data on the bus under control of the master device.

The bq2416x device works as a slave and supports the following data transfer modes, as defined in the I<sup>2</sup>C Bus Specification: standard mode (100kbps) and fast mode (400kbps). The interface adds flexibility to the battery charging solution, enabling most functions to be programmed to new values depending on the instantaneous application requirements. Register contents remain intact as long as battery voltage remains above 2.5V (typical). The I<sup>2</sup>C circuitry is powered from VBUS when a supply is connected. If the VBUS supply is not connected, the I<sup>2</sup>C circuitry is powered from the battery through BAT. The battery voltage must stay above 2.5V with no input connected in order to maintain proper operation.

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The data transfer protocol for standard and fast modes is exactly the same; therefore, they are referred to as the F/S-mode in this document. The bq2416x devices only support 7-bit addressing. The device 7-bit address is defined as '1101011' (6Bh).

#### **F/S Mode Protocol**

The master initiates data transfer by generating a start condition. The start condition is when a high-to-low transition occurs on the SDA line while SCL is high, as shown in Figure 28. All I<sup>2</sup>C-compatible devices should recognize a start condition.



Figure 28. START and STOP Condition

The master then generates the SCL pulses, and transmits the 8-bit address and the read/write direction bit R/W on the SDA line. During all transmissions, the master ensures that data is valid. A valid data condition requires the SDA line to be stable during the entire high period of the clock pulse (see Figure 29). All devices recognize the address sent by the master and compare it to their internal fixed addresses. Only the slave device with a matching address generates an acknowledge (see Figure 30) by pulling the SDA line low during the entire high period of the ninth SCL cycle. Upon detecting this acknowledge, the master knows that communication link with a slave has been established.



Figure 29. Bit Transfer on the Serial Interface

The master generates further SCL cycles to either transmit data to the slave (R/W bit 1) or receive data from the slave (R/W bit 0). In either case, the receiver needs to acknowledge the data sent by the transmitter. So an acknowledge signal can either be generated by the master or by the slave, depending on which one is the receiver. The 9-bit valid data sequences consisting of 8-bit data and 1-bit acknowledge can continue as long as necessary. To signal the end of the data transfer, the master generates a stop condition by pulling the SDA line from low to high while the SCL line is high (see Figure 31). This releases the bus and stops the communication link with the addressed slave. All I<sup>2</sup>C compatible devices must recognize the stop condition. Upon the receipt of a stop condition, all devices know that the bus is released, and wait for a start condition followed by a matching address. If a transaction is terminated prematurely, the master needs sending a STOP condition to prevent the slave I<sup>2</sup>C logic from remaining in an incorrect state. Attempting to read data from register addresses not listed in this section result in FFh being read out.



Condition

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Figure 31. Bus Protocol

Product Folder Links: *bq24160 bq24160A bq24161 bq24161B bq24163 bq24168* 



## **REGISTER DESCRIPTION**

#### Status/Control Register (READ/WRITE)

Memory location: 00, Reset state: 0xxx 0xxx

BIT	NAME	Read/Write	FUNCTION
B7 (MSB)	TMR_RST	Read/Write	Write: TMR_RST function, write "1" to reset the watchdog timer (auto clear) Read: Always 0 (bq24160/1/3 only)
B6	STAT_2	Read only	000- No Valid Source Detected
B5	STAT_1	Read only	001- IN Ready (shows preferred source when both connected)
B4	STAT_0	Read only	010- USB Ready (shows preferred source when both connected) 011- Charging from IN 100- Charging from USB 101- Charge Done 110- NA 111- Fault
B3	SUPPLY_SEL	Read/Write	0-IN has precedence when both supplies are connected 1-USB has precedence when both supplies are connected (default 0)
B2	FAULT_2	Read only	000-Normal
B1	FAULT_1	Read only	001- Thermal Shutdown
B0 (LSB)	FAULT_0	Read only	010- Battery Temperature Fault 011- Watchdog Timer Expired (bq24160/1/1B/3 only) 100- Safety Timer Expired (bq24160/1/1B/3 only) 101- IN Supply Fault 110- USB Supply Fault 111- Battery Fault

#### SUPPLY\_SEL Bit (Supply Precedence Selector)

The SUPPLY\_SEL bit selects which supply has precedence when both supplies are present. In cases where both supplies are connected, they must remain isolated from each other which means only one is allowed to charge the battery. Write a "1" to SUPPLY\_SEL to select the USB input to have precedence. Write a "0" to select the IN input.

#### STAT\_x and FAULT\_x Bits

The STAT\_x show the current status of the device and are updated dynamically as the IC changes state. The FAULT\_x bits show faults that have occurred and are only cleared by reading the bits, assuming the fault no longer exists. If multiple faults occur, the first one is the one that is shown.

#### Battery/ Supply Status Register (READ/WRITE)

Memory location: 01, Reset state: xxxx 0xxx

BIT	NAME	Read/Write	FUNCTION	
B7 (MSB)	INSTAT1	Read Only	00-Normal	
B6	INSTAT0	Read Only	01-Supply OVP 10-Weak Source Connected (No Charging) 11- V <sub>IN</sub> <v<sub>UVLO</v<sub>	
B5	USBSTAT1	Read Only	00-Normal	
B4	USBSTAT0	Read Only	01-Supply OVP 01-Weak Source Connected (No Charging) 11- V <sub>USB</sub> <v<sub>UVLO</v<sub>	
B3	OTG_LOCK	Read/Write	<ul> <li>0 – No OTG supply present. Use USB input as normal.</li> <li>1 – OTG supply present. Lockout USB input for charging.</li> <li>(default 0)</li> </ul>	
B2	BATSTAT1	Read Only	00-Battery Present and Normal	
B1	BATSTAT0	Read Only	01-Battery OVP 10-Battery Not Present 11- NA	

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BIT	NAME	Read/Write	FUNCTION
B0 (LSB)	EN_NOBATOP	Read/ Write	0-Normal Operation 1-Enables No Battery Operation when termination is disabled (default 0)

#### OTG\_LOCK Bit (USB Lockout)

The OTG\_LOCK bit is used to prevent any charging from USB input regardless of the SUPPLY\_SEL bit and IN supply status. For systems using OTG supplies, it is not desirable to charge from an OTG source. Doing so would mean draining the battery by allowing it to effectively charge itself. Write a "1" to OTG\_LOCK to lock out the USB input. Write a "0" to OTG\_LOCK to return to normal operation. During OTG lock, the USB input is ignored and DRV does not come up. The watchdog timer must be reset while in USB\_LOCK to maintain the USB lockout state. This prevents the USB input from being permanently locked out for cases where the host loses I2C communication with OTG\_LOCK set (i.e., discharged battery from OTG operation). See the *Safety Timer and Watchdog Timer* section for more details.

#### EN\_NOBATOP (No Battery Operation with Termination Disabled)

The EN\_NOBATOP bit is used to enable operation when termination is disabled and no battery is connected. This is useful for cases where the PA is connected to the BAT pin and it desired to do a GSM calibration in the factory. For this application, the TE bit (Bit 2 in Register 0x02h) should be set to a "0" to disable termination and the EN\_NOBATOP should be set to a "1". This feature should not be used during normal operation as it disables the BATOVP and the reverse boost protection circuits.

#### Control Register (READ/WRITE)

Memory location: 02, Reset state: 1000 1100

BIT	NAME	Read/Write	FUNCTION
B7 (MSB)	RESET	Write only	Write: 1 – Reset all registers to default values 0 – No effect Read: always get "1"
B6	IUSB_LIMIT_2	Read/Write	000 – USB2.0 host with 100mA current limit
B5	IUSB_LIMIT_1	Read/Write	001 – USB3.0 host with 150mA current limit
B4	IUSB_LIMIT _0	Read/Write	<ul> <li>010 - USB2.0 host with 500mA current limit</li> <li>011 - USB host/charger with 800mA current limit</li> <li>100 - USB3.0 host with 900mA current limit</li> <li>101 - USB host/charger with 1500mA current limit</li> <li>110-111 - NA (default 000<sup>(1)</sup>)</li> </ul>
B3	EN_STAT	Read/Write	<ul> <li>1 – Enable STAT output to show charge status,</li> <li>0-Disable STAT output for charge status. Fault interrupts are still show even when EN_STAT = 0. (default 1)</li> </ul>
B2	TE	Read/Write	<ul><li>1 – Enable charge current termination,</li><li>0-Disable charge current termination (default 1)</li></ul>
B1	CE	Read/Write	1 – Charging is disabled 0 – Charging enabled (default 0 bq24160/1/3/8, 1 bq24161B)
B0 (LSB)	HZ_MODE	Read/Write	<ul><li>1 – High impedance mode</li><li>0 – Not high impedance mode (default 0)</li></ul>

(1) When in DEFAULT mode, the D+/D- (bq24160) or PSEL (bq24161/8) inputs determine the input current limit for the USB input.

#### **RESET Bit**

The RESET bit in the control register (0x02h) is used to reset all the charge parameters. Write "1" to RESET bit to reset all the registers to default values and place the bq2416x into DEFAULT mode and turn off the watchdog timer. The RESET bit is automatically cleared to zero once the bq2416x enters DEFAULT mode.

#### **CE** Bit (Charge Enable)



The  $\overline{CE}$  bit in the control register (0x02h) is used to disable or enable the charge process. A low logic level (0) on this bit enables the charge and a high logic level (1) disables the charge. When charge is disabled, the SYS output regulates to VSYS(REG) and battery is disconnected from the SYS. Supplement mode is still available if the system load demands cannot be met by the supply.



#### HZ\_MODE Bit (High Impedance Mode Enable)

The HZ\_MODE bit in the control register (0x02h) is used to disable or enable the high impedance mode. A low logic level (0) on this bit enables the IC and a high logic level (1) puts the IC in a low quiescent current state called high impedance mode. When in high impedance mode, the converter is off and the battery FET and BGATE are on. The load on SYS is supplied by the battery.

#### Control/Battery Voltage Register (READ/WRITE)

Memory location: 03, Reset state: 0001 0100

BIT	NAME	Read/Write	FUNCTION
B7 (MSB)	V <sub>BREG5</sub>	Read/Write	Battery Regulation Voltage: 640 mV (default 0)
B6	V <sub>BREG4</sub>	Read/Write	Battery Regulation Voltage: 320 mV (default 0)
B5	V <sub>BREG3</sub>	Read/Write	Battery Regulation Voltage: 160 mV (default 0)
B4	V <sub>BREG2</sub>	Read/Write	Battery Regulation Voltage: 80 mV (default 1)
B3	V <sub>BREG1</sub>	Read/Write	Battery Regulation Voltage: 40 mV (default 0)
B2	V <sub>BREG0</sub>	Read/Write	Battery Regulation Voltage: 20 mV (default 1)
B1	I <sub>inlimit</sub>	Read/Write	Input Limit for IN input- 0 – 1.5A 1 – 2.5A (default 0)
B0 (LSB)	D+/DEN	Read/Write	0 – Normal state, D+/D- Detection done 1 – Force D+/D– Detection. Returns to "0" after detection is done. (default 0)

• Charge voltage range is 3.5V–4.44V with the offset of 3.5V and step of 20mV (default 3.6V).

 Before writing to increase VBATREG register following a BATOVP event (e.g., IN or USB voltage is applied, IC remains in DEFAULT mode and then VBAT>3.6V is attached), toggle the HiZ bit or CD pin to clear the BATOVP fault.

## Vender/Part/Revision Register (READ only)

Memory location: 04, Reset state: 0100 0000

BIT	NAME	Read/Write	FUNCTION
B7 (MSB)	Vender2	Read only	Vender Code: bit 2 (default 0)
B6	Vender1	Read only	Vender Code: bit 1 (default 1)
B5	Vender0	Read only	Vender Code: bit 0 (default 0)
B4	PN1	Read only	For I <sup>2</sup> C Address 6Bh:
B3	PN0	Read only	00: bq2416x 01–11: Future product spins
B2	Revision2	Read only	000: Revision 1.0
B1	Revision1	Read only	001: Revision 1.1
B0 (LSB)	Revision0	Read only	<ul> <li>010: Revision 2.0</li> <li>011: Revision 2.1</li> <li>100: Revision 2.2</li> <li>101: Revision 2.3</li> <li>110-111: Future Revisions</li> </ul>

TEXAS INSTRUMENTS

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## Battery Termination/Fast Charge Current Register (READ/WRITE)

Memory location: 05, Reset state: 0011 0010

BIT	NAME	Read/Write	FUNCTION
B7 (MSB)	I <sub>CHRG4</sub>	Read/Write	Charge current: 1200mA – (default 0)
B6	I <sub>CHRG3</sub>	Read/Write	Charge current: 600mA – (default 0)
B5	I <sub>CHRG2</sub>	Read/Write	Charge current: 300mA – (default 1)
B4	I <sub>CHRG1</sub>	Read/Write	Charge current: 150mA – (default 1)
B3	I <sub>CHRG0</sub>	Read/Write	Charge current: 75 mA (default 0)
B2	I <sub>TERM2</sub>	Read/Write	Termination current sense voltage: 200mA (default 0)
B1	I <sub>TERM1</sub>	Read/Write	Termination current sense voltage: 100mA (default 1)
B0 (LSB)	I <sub>TERMO</sub>	Read/Write	Termination current sense voltage: 50mA (default 0)

• Charge current sense offset is 550mA and default charge current is 1000mA.

• Termination threshold offset is 50mA and default termination current is 150mA

## VIN-DPM Voltage/ DPPM Status Register

Memory location: 06, Reset state: xx00 0000

BIT	NAME	Read/Write	FUNCTION
B7(MSB)	MINSYS_STATUS	Read Only	<ol> <li>Minimum System Voltage mode is active (V<sub>BAT</sub><v<sub>MINSYS)</v<sub></li> <li>Minimum System Voltage mode is not active</li> </ol>
B6	DPM_STATUS	Read Only	1 – $V_{IN}$ -DPM mode is active 0 – $V_{IN}$ -DPM mode is not active
B5	V <sub>INDPM2(USB)</sub>	Read/Write	USB input V <sub>IN-DPM</sub> voltage: 320mV (default 0)
B4	VINDPM1(USB)	Read/Write	USB input V <sub>IN-DPM</sub> voltage: 160mV (default 0)
B3	VINDPM0(USB)	Read/Write	USB input V <sub>IN-DPM</sub> voltage: 80mV (default 0)
B2	VINDPM2(IN)	Read/Write	IN input V <sub>IN-DPM</sub> voltage: 320mV (default 0)
B1	V <sub>INDPM1(IN)</sub>	Read/Write	IN input V <sub>IN-DPM</sub> voltage: 160mV (default 0)
B0(LSB)	VINDPM0(IN)	Read/Write	IN input V <sub>IN-DPM</sub> voltage: 80mV (default 0)

• V<sub>IN-DPM</sub> voltage offset is 4.20V and default V<sub>IN-DPM</sub> threshold is 4.20V.



#### Safety Timer/ NTC Monitor Register (READ/WRITE)

Memory location: 07, Reset state: 1001 1xxx

BIT	NAME	Read/Write	FUNCTION
B7 (MSB)	2XTMR_EN	Read/Write	1 – Timer slowed by 2x when in thermal regulation, input current limit, $V_{\text{IN}\_\text{DPM}}$ or DPPM
			0 – Timer not slowed at any time (default 0) (bq24160/1 only)
B6	TMR_1	Read/Write	Safety Timer Time Limit –
B5	TMR_2	Read/Write	00 – 27 minute fast charge
			01 – 6 hour fast charge
			10 – 9 hour fast charge
			11 – Disable safety timers (default 00) (bq24160/1 only)
B4	NA	Read/Write	NA
B3	TS_EN	Read/Write	0 – TS function disabled
			1 – TS function enabled (default 1)
B2	TS_FAULT1	Read only	TS Fault Mode:
B1	TS FAULT0	Read only	00 – Normal, No TS fault
		rioda enily	01 – TS temp < T <sub>COLD</sub> or TS temp > T <sub>HOT</sub> (Charging suspended)
			$10 - T_{COOL} > TS$ temp > $T_{COLD}$ (Charge current reduced by half, bq24160 only)
			11 – T <sub>WARM</sub> < TS temp < T <sub>HOT</sub> (Charge voltage reduced by 140mV, bq24160 only)
B0 (LSB)	LOW_CHG	Read/ Write	0 – Charge current as programmed in Register 0x05
			1 – Charge current is half programmed value in Register 0x05
			(default 0)

#### 2xTMR\_EN Bit (2x Timer Enable)

The 2xTMR\_EN bit is used to slow down the timer when charge current is reduced by the system load. When 2xTMR\_EN is a "1", the safety timer is slowed to half speed effectively doubling the timer time. The conditions that activate the 2x timer are: Input Current Limit, V<sub>INDPM</sub>, Thermal Regulation, LOW\_CHG, BATSHRT and TS Cool. When 2xTMR\_EN is a "0", the timer operates at normal speed in all conditions.

#### LOW\_CHG Bit (Low Charge Mode Enable)

The LOW\_CHG bit is used to reduce the charge current from the programmed value. This feature is used by systems where battery NTC is monitored by the host and requires a reduced charge current setting or by systems that need a "preconditioning" current for low battery voltages. Write a "1" to this bit to charge at half of the programmed charge current (bq24160/1/3/8). Write a "0" to this bit to charge at the programmed charge current.



## **APPLICATION INFORMATION**

#### **Output Inductor and Capacitor Selection Guidelines**

When selecting an inductor, several attributes must be examined to find the right part for the application. First, the inductance value should be selected. The bq2416x is designed to work with  $1.5\mu$ H to  $2.2\mu$ H inductors. The chosen value will have an effect on efficiency and package size. Due to the smaller current ripple, some efficiency gain is reached using the  $2.2\mu$ H inductor, however, due to the physical size of the inductor, this may not be a viable option. The  $1.5\mu$ H inductor provides a good tradeoff between size and efficiency.

Once the inductance has been selected, the peak current must be calculated in order to choose the current rating of the inductor. Use Equation 5 to calculate the peak current.

$$I_{\text{PEAK}} = I_{\text{LOAD}(\text{MAX})} \times \left(1 + \frac{\%_{\text{RIPPPLE}}}{2}\right)$$

(5)

The inductor selected must have a saturation current rating greater than or equal to the calculated  $I_{PEAK}$ . Due to the high currents possible with the bq2416x, a thermal analysis must also be done for the inductor. Many inductors have a 40°C temperature-rise rating. The DC component of the current can cause a 40°C temperature rise above the ambient temperature in the inductor. For this analysis, the typical load current may be used adjusted for the duty cycle of the load transients. For example, if the application requires a 1.5A DC load with peaks at 2.5A 20% of the time, a  $\Delta$ 40°C temperature rise current must be greater than 1.7A:

$$I_{\text{TEMPRISE}} = I_{\text{LOAD}} + D \times (I_{\text{PEAK}} - I_{\text{LOAD}}) = 1.5A + 0.2 \times (2.5A - 1.5A) = 1.7A$$
(6)

The bq2416x provides internal loop compensation. Using this scheme, the bq2416x is stable with  $10\mu$ F to  $200\mu$ F of local capacitance on the SYS output. The capacitance on the SYS rail can be higher if distributed amongst the rail. To reduce the output voltage ripple, a ceramic capacitor with the capacitance between  $10\mu$ F and  $47\mu$ F is recommended for local bypass to SYS. A  $47\mu$ F bypass capacitor is recommended for optimal transient response.



#### **PCB Layout Guidelines**

It is important to pay special attention to the PCB layout. Figure 32 provides a sample layout for the high current paths of the bq2416x. A list of layout guidelines follows.



WCSP



QFN

#### Figure 32. Recommended bq2416x PCB Layout

- To obtain optimal performance, the power input capacitors, connected from the PMID input to PGND, must be placed as close as possible to the bq2416x
- Minimize the amount of inductance between BAT and the postive connection of the battery terminal. If a large parasitic board inductance on BAT is expected, increase the bypass capacitance on BAT.
- Place 4.7µF input capacitor as close to PMID\_ pin and PGND pin as possible to make high frequency current loop area as small as possible. Place 1µF input capacitor GNDs as close to the respective PMID cap GND and PGND pins as possible to minimize the ground difference between the input and PMID\_.
- The traces from the input connector to the inputs of the bq2416x should be as wide as possible to minimize the impedance in the line. Although the VINDPM feature will allow operation from input sources having high resistances(impedances), the bq2416x input pins (IN and USB) have been optimized to connect to input sources with no more than 350mohm of input resistance, including cables and PCB traces
- The local bypass capacitor from SYS to GND should be connected between the SYS pin and PGND of the IC. The intent is to minimize the current path loop area from the SW pin through the LC filter and back to the PGND pin.
- Place all decoupling capacitors close to their respective IC pins and as close as to PGND (do not place components such that routing interrupts power stage currents). All small control signals should be routed away from the high-current paths.
- The PCB should have a ground plane (return) connected directly to the return of all components through vias (two vias per capacitor for power-stage capacitors, one via per capacitor for small-signal components). It is also recommended to put vias inside the PGND pads for the IC, if possible. A star ground design approach is typically used to keep circuit block currents isolated (high-power/low-power small-signal) which reduces noisecoupling and ground-bounce issues. A single ground plane for this design gives good results. With this small layout and a single ground plane, there is no ground-bounce issue, and having the components segregated minimizes coupling between signals.
- The high-current charge paths into IN, USB, BAT, SYS and from the SW pins must be sized appropriately for the maximum charge current in order to avoid voltage drops in these traces. The PGND pins should be connected to the ground plane to return current through the internal low-side FET.
- For high-current applications, the balls for the power paths should be connected to as much copper in the board as possible. This allows better thermal performance because the board conducts heat away from the IC.

## **REVISION HISTORY**

#### Changes from Original (November 2011) to Revision A

•	Changed V <sub>BATREG</sub> - Voltage regulation accuracy	5
•	Changed the USB Pin numbers in the YFF pachkage for bq24160/3 From: A5-A6 To: A5-A7	
•	Changed Figure 3	11
•	Changed Figure 4	11

#### Changes from Revision A (March 2011) to Revision B

CI	hanges from Revision B (September 2012) to Revision C	Page
•	Changed Figure 32	. 35
•	Changed From: $V_{WARM} < V_{TS} < V_{HOT}$ To: $V_{WARM} > V_{TS} > V_{HOT}$ , and Changed From: $V_{COLD} < V_{TS} < V_{COOL}$ To: $V_{COLD} > V_{TS} > V_{COOL}$ in the External NTC Monitoring (TS) section	22
•	Changed text From: "battery FET (Q6)" To: "battery FET (Q4)" in the Battery Only Connected section	. 18
•	Changed the Ordering Information table to include bq24161B	3
•	Added device bq24161B to the data sheet	1

#### Changes from Revision B (September 2012) to Revision C

	Added device bq24160A to the data sheet Changed the Ordering Information table to include bq24160A	1
_		_

#### Changes from Revision C (October 2012) to Revision D

•	Changed the Ordering Information table to include the WSCP package for bq24161BRGR and bq24161BYFF	3
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## PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Sampl
BQ24160ARGER	ACTIVE	VQFN	RGE	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR		BQ 24160A	Sampl
BQ24160ARGET	ACTIVE	VQFN	RGE	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR		BQ 24160A	Sampl
BQ24160RGER	ACTIVE	VQFN	RGE	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ 24160	Samp
BQ24160RGET	ACTIVE	VQFN	RGE	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ 24160	Samp
BQ24160YFFR	ACTIVE	DSBGA	YFF	49	3000	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	-40 to 85	BQ24160	Samp
BQ24160YFFT	ACTIVE	DSBGA	YFF	49	250	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	-40 to 85	BQ24160	Samp
BQ24161BRGER	ACTIVE	VQFN	RGE	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ 24161B	Samp
BQ24161BRGET	ACTIVE	VQFN	RGE	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ 24161B	Samp
BQ24161RGER	ACTIVE	VQFN	RGE	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ 24161	Samp
BQ24161RGET	ACTIVE	VQFN	RGE	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ 24161	Samp
BQ24161YFFR	ACTIVE	DSBGA	YFF	49	3000	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	-40 to 85	BQ24161	Samp
BQ24161YFFT	ACTIVE	DSBGA	YFF	49	250	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	-40 to 85	BQ24161	Samp
BQ24163RGER	ACTIVE	VQFN	RGE	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ 24163	Samp
BQ24163RGET	ACTIVE	VQFN	RGE	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ 24163	Samp
BQ24163YFFR	PREVIEW	DSBGA	YFF	49	3000	TBD	Call TI	Call TI	-40 to 85	BQ24163	
BQ24163YFFT	PREVIEW	DSBGA	YFF	49	250	TBD	Call TI	Call TI	-40 to 85	BQ24163	
BQ24168RGER	ACTIVE	VQFN	RGE	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ 24168	Samp
BQ24168RGET	ACTIVE	VQFN	RGE	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ 24168	Samp



24-Jan-2013

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
BQ24168YFFR	ACTIVE	DSBGA	YFF	49	3000	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	-40 to 85	BQ24168	Samples
BQ24168YFFT	ACTIVE	DSBGA	YFF	49	250	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	-40 to 85	BQ24168	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> Only one of markings shown within the brackets will appear on the physical device.

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# PACKAGE MATERIALS INFORMATION

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# TAPE AND REEL INFORMATION





## QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
BQ24160ARGER	VQFN	RGE	24	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24160ARGET	VQFN	RGE	24	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24160RGER	VQFN	RGE	24	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24160RGET	VQFN	RGE	24	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24160YFFR	DSBGA	YFF	49	3000	180.0	8.4	2.93	2.93	0.81	4.0	8.0	Q1
BQ24160YFFT	DSBGA	YFF	49	250	180.0	8.4	2.93	2.93	0.81	4.0	8.0	Q1
BQ24161BRGER	VQFN	RGE	24	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24161BRGET	VQFN	RGE	24	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24161RGER	VQFN	RGE	24	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24161RGET	VQFN	RGE	24	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24161YFFR	DSBGA	YFF	49	3000	180.0	8.4	2.93	2.93	0.81	4.0	8.0	Q1
BQ24161YFFT	DSBGA	YFF	49	250	180.0	8.4	2.93	2.93	0.81	4.0	8.0	Q1
BQ24163RGER	VQFN	RGE	24	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24163RGET	VQFN	RGE	24	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24168RGER	VQFN	RGE	24	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24168RGET	VQFN	RGE	24	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ24168YFFR	DSBGA	YFF	49	3000	180.0	8.4	2.93	2.93	0.81	4.0	8.0	Q1
BQ24168YFFT	DSBGA	YFF	49	250	180.0	8.4	2.93	2.93	0.81	4.0	8.0	Q1

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# PACKAGE MATERIALS INFORMATION

16-Nov-2012



Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
BQ24160ARGER	VQFN	RGE	24	3000	367.0	367.0	35.0
BQ24160ARGET	VQFN	RGE	24	250	210.0	185.0	35.0
BQ24160RGER	VQFN	RGE	24	3000	367.0	367.0	35.0
BQ24160RGET	VQFN	RGE	24	250	210.0	185.0	35.0
BQ24160YFFR	DSBGA	YFF	49	3000	210.0	185.0	35.0
BQ24160YFFT	DSBGA	YFF	49	250	210.0	185.0	35.0
BQ24161BRGER	VQFN	RGE	24	3000	367.0	367.0	35.0
BQ24161BRGET	VQFN	RGE	24	250	210.0	185.0	35.0
BQ24161RGER	VQFN	RGE	24	3000	367.0	367.0	35.0
BQ24161RGET	VQFN	RGE	24	250	210.0	185.0	35.0
BQ24161YFFR	DSBGA	YFF	49	3000	210.0	185.0	35.0
BQ24161YFFT	DSBGA	YFF	49	250	210.0	185.0	35.0
BQ24163RGER	VQFN	RGE	24	3000	367.0	367.0	35.0
BQ24163RGET	VQFN	RGE	24	250	210.0	185.0	35.0
BQ24168RGER	VQFN	RGE	24	3000	367.0	367.0	35.0
BQ24168RGET	VQFN	RGE	24	250	210.0	185.0	35.0
BQ24168YFFR	DSBGA	YFF	49	3000	210.0	185.0	35.0
BQ24168YFFT	DSBGA	YFF	49	250	210.0	185.0	35.0

# **MECHANICAL DATA**



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Quad Flatpack, No-Leads (QFN) package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions. F. Falls within JEDEC MO-220.
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## RGE (S-PVQFN-N24)

## PLASTIC QUAD FLATPACK NO-LEAD

#### THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



#### NOTES: A. All linear dimensions are in millimeters



RGE (S-PVQFN-N24)

PLASTIC QUAD FLATPACK NO-LEAD



NOTES:

A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.



YFF (R-XBGA-N49)

DIE-SIZE BALL GRID ARRAY



- В. This drawing is subject to change without notice.
- C. NanoFree™ package configuration.
- 🖄 The package size (Dimension D and E) of a particular device is specified in the device Product Data Sheet version of this drawing, in case it cannot be found in the product data sheet please contact a local TI representative.
- E. Reference Product Data Sheet for array population. 7 x 7 matrix pattern is shown for illustration only.
- F. This package contains Pb-free balls.

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